

REMARKS

The Examiner's Action mailed on June 5, 2007, has been received and its contents carefully considered. Additionally attached to this Amendment is a Petition for a two-month Extension of Time extending the response period to November 5, 2007.

In this Amendment, Applicants have amended claim 5, and added claims 37 and 38. Claim 5 is the independent claim, and claims 2, 5-6, 9-10, 18, 20 and 37-38 are pending in the application. For at least the following reasons, it is submitted that this application is in condition for allowance.

The Examiner has objected to the specification for having informalities. In response, the specification has been amended to correct the matters specifically noted by the Examiner. It is submitted that the specification complies with all official requirements, and it is requested that this objection be withdrawn.

The Examiner has rejected claims 2, 5-6, 9-10 and 18 as being anticipated by *Konuma et al.* (US 2001/0019133) (hereafter simply *Konuma*). It is submitted that these claims are *prima facie* patentably distinguishable over the cited reference for at least the following reasons.

Applicants' amended independent claim 5 is directed to a semiconductor apparatus which includes a silicon substrate, a planarized region defined over the silicon substrate, a planarized film disposed over the planarized region, and a semiconductor thin film. Claim 5 recites that a flatness of the planarized region is

not more than 10 nanometers, and a surface of the planarized film on a side of the semiconductor thin film has been subjected to a planarizing process. The semiconductor thin film is disposed over the planarized film. The claim further recites that the semiconductor thin film is made of a compound semiconductor as a main material. This invention has the advantages discussed in Applicants' specification, and is neither disclosed nor suggested by the cited reference.

Konuma is directed to an EL (electro luminescence) device which includes, *inter alia*, an insulating film 39, a pixel electrode 40 and protective portions 41a and 41b. The insulating film 39 disclosed by *Konuma* is formed on a first passivation film 38 so as to cover respective TFTs (see *Konuma*, paragraph [0013]).

The Examiner equates the insulating film 39 disclosed by *Konuma* with the planarized region recited in claim 5. However, *Konuma* does not disclose or suggest that a flatness of the insulating film 39 is not more than 10 nanometers, as recited in claim 5. Accordingly, *Konuma* does not disclose or suggest the planarized region, as recited in claim 5.

As such, it is submitted that Applicants' independent claim 5 has not been anticipated by the cited reference. It is thus requested that this rejection be withdrawn and that this claim be allowed.

Because claims 2, 6, 9-10 and 18 depend from independent claim 5, these claims are not anticipated by the cited reference for at least the same reasons as claim 5, as well as for the additional features recited therein. In addition, the

Examiner equates *Konuma's* protective portions 41a and 41b with the interdielectric layer recited in claim 6, and further equates the combination of *Konuma's* pixel electrode 40 and protective portions 41a and 41b with the planarized film recited in claim 6, asserting that *Konuma's* combination (40/41a/41b) is a thin film that is planarized in a sub-region. However, there is no disclosure or suggestion that *Konuma's* protective portions 41a and 41b are planarized together with the pixel electrode 40, so as to form a planarized film as recited in claim 6. Rather, the thickness of a rising portion in cross section of the protective portions 41a and 41b from the pixel electrode 40 is 0.1 to 1 μm (see paragraph [0069], Figure 2). Thus, *Konuma's* combination (40/41a/41b) is not equivalent to the planarized film recited in claim 6. Likewise, *Konuma's* protective portions 41a and 41b are not equivalent to the interdielectric layer recited in claim 6.

The Examiner's Action has rejected claim 20 as being obvious over *Konuma* in view of *Tsuruoka et al.* (JP 2001/167874). Because *Tsuruoka et al.* do not overcome the above noted deficiencies of *Konuma*, and because claim 20 depends from independent claim 5, it is submitted that claim 20 is *prima facie* patentably distinguishable over the cited references for at least the same reasons as independent claim 5, from which this claim depend, as well as for the additional features recited therein. In addition, a head of an optical printer disclosed by *Tsuruoka et al.* is made of an organic EL element. Since the organic EL element is made of an organic material, it is not equivalent to the claimed compound

semiconductor. It is requested that the claim be allowed and that this rejection be withdrawn.

New claims 37 and 38 have been added. Claim 37 is supported by the specification at page 8, lines 4-6, and claim 38 is supported by the specification at pages 5-12 and Figures 1-6. Because claims 37 and 38 depend from independent claim 5, it is submitted that these claims are *prima facie* patentably distinguishable over the cited references for at least the same reasons as independent claim 5, as well as for the additional features recited therein.

In addition, claim 37 recites that the interdielectric layer of the planarized film has the same thickness as that of the electrically conductive layer of the planarized film, which is not disclosed or suggested by the cited references. As stated above, in *Konuma*, the thickness of a rising portion in cross section of the protective portions 41a and 41b from the pixel electrode 40 is 0.1 to 1 μm (see paragraph [0069], Figure 2). Thus, the thickness of the protective portions 41a and 41b disclosed by *Konuma* is not the same as that of the pixel electrode 40.

Further, claim 38 recites that an entire portion of the planarized film is directly disposed on an upper surface of the planarized region, and an entire lower surface of the planarized film contacts the upper surface of the planarized region, which is not disclosed or suggested by the cited references. The pixel electrode 40 disclosed by *Konuma* is connected to the drain wiring 37 (see paragraph [0063], Figures 1A-1C and 2). The portion of *Konuma*'s pixel electrode 40 that is connected to the drain wiring 37 is not directly disposed on the insulating film 39.

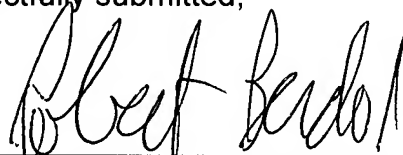
Rather, that portion of electrode 40 is only disposed on the wiring 37. Similarly, due to the portion of *Konuma*'s pixel electrode 40 connected to the wiring 37, an entire lower surface of *Konuma*'s pixel electrode 40 does not contact the upper surface of the insulating film 39, as recited in claim 38.

It is submitted that this application is now in condition for allowance. Such action and the passing of this case to issue are requested.

Should the Examiner feel that a conference would help to expedite the prosecution of the application, the Examiner is hereby invited to contact the undersigned counsel to arrange for such an interview.

The extension fee is submitted herewith. Should this remittance be accidentally missing, or should any additional fees be required, however, the Commissioner is hereby authorized to charge such fees to our Deposit Account No. 18-0002 and advise us accordingly.

Respectfully submitted,



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Date

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